Application/Control No. Applicant(s)/Patent Under Reexamination 10/740,465 BAEK ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2629 Seokyun Moon **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY 04-2002 345/204 US-6,377,251 Takasu et al. Α В US-С US-US-D US-E F US-G US-USн US-US-US-Κ

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